

Title (en)
ELECTRON MICROSCOPE, AND METHOD FOR OBSERVING MEASUREMENT SAMPLE

Title (de)
ELEKTRONENMIKROSKOP UND VERFAHREN ZUR BEOBACHTUNG EINER MESSPROBE

Title (fr)
MICROSCOPE ÉLECTRONIQUE ET PROCÉDÉ D'OBSERVATION D'ÉCHANTILLON DE MESURE

Publication
EP 3757558 A4 20211117 (EN)

Application
EP 19757961 A 20190218

Priority
• JP 2018031379 A 20180223
• JP 2019005874 W 20190218

Abstract (en)
[origin: EP3757558A1] Provided are an electron microscope and a method for observing a measurement sample, which enable non-destructive observation. An electron microscope (1) includes: a laser light source (2) for generating a CW laser (7); an irradiation lens system (focusing lens (4) and objective lens (6)) for irradiating a measurement sample (30) with the CW laser (7); an energy analyzer (22) for dispersing, depending on energy, photoelectrons emitted from the measurement sample (30) by the CW laser (7); an energy slit (23) for allowing a photoelectron with a specified energy to pass; an electron beam detector (25) for detecting the photoelectron passed through the energy slit (23); a first electron lens system (21) for focusing the photoelectrons emitted from the measurement sample (30) onto the energy analyzer (22); and a second electron lens system (24) for projecting the photoelectron passed through the energy slit (23) onto the electron beam detector (25).

IPC 8 full level
G01N 23/227 (2018.01); **G02B 21/00** (2006.01); **H01J 37/285** (2006.01); **G01R 31/265** (2006.01)

CPC (source: EP KR US)
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Citation (search report)
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• See also references of WO 2019163715A1

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